


Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/605,215	CHEN ET AL.	
	Examiner	Art Unit	
	Junghwa M. Im	2811	

SEARCHED			
Class	Subclass	Date	Examiner
257	666	2/5/2005	JMI
	778		
	797		
	738		
	738		
	773		

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST (USPAT, US PUB, EPO, JPO, DER)	2/5/2005	JMI